Message from the Symposium Chair

On behalf of the members of the organizing committee of the Tenth Asian Test Symposium (ATS'01), I would like to welcome you to ATS'01 in Kyoto, Japan. ATS'01 follows the tradition to present state-of-the-art ideas and exchange opinions in the field of testing. It is a great pleasure for us to celebrate the tenth anniversary of ATS at the beginning of the new century.

In November, it is the best season to enjoy sightseeing of Kyoto, the ancient capital of Japan. There are more than two thousand shrines and temples, and seventeen of them have been inscribed on the UNESCO World Cultural Heritage List as Historic Monuments of Ancient Kyoto. Before or after the symposium you can visit these shrines and temples and enjoy the sceneries with changing colors of trees.

The success of a symposium depends on the quality of the technical program. Many excellent papers were submitted not only from Asia but also from all over the world. I would like to express my appreciation to Prof. Hiromi Hiraishi, the Program Chair, to Dr. Kazumi Hatayama, the Program Vice-Chair, and to every Program Committee member for their collective effort on paper selection and establishing the program. Further, it is our honor that we could invite Dr. Janusz Rajski as a keynote address speaker, Prof. Ad J. van de Goor, Dr. Erik Jan Marinissen and Dr. Yervant Zorian as tutorial lecturers.

ATS'01 is sponsored by the IEEE Computer Society Test Technology Technical Council, in cooperation with Technical Group on Fault Tolerant Systems of IEICE, Special Interest Group on System LSI Design Methodology of IPS Japan and the Research Institute of Advanced Technology of Kyoto Sangyo University. I would like to take this opportunity to express my appreciation for their sponsoring and supporting this symposium. I also would like to thank Prof. Kozo Kinoshita, the Asian and Pacific Group Chair of IEEE Computer Society Test Technology Technical Council for giving us an opportunity of holding ATS'01 in Kyoto, Japan.

On a personal note, I would like to pay tribute to the memory of Professor Teruhiko Yamada, who ought to be the Symposium Chair but sadly passed away in the year before last. In fact, we owe the initial planning of this symposium to him.

Finally, let me express the hope that all participants of ATS'01 will be stimulated by what they learn to contribute to future progress in the field of testing.

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